

## SUD50P08-25L-E3-VB Datasheet

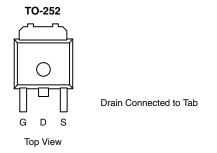
# P-Channel 100-V (D-S) 175 °C MOSFET

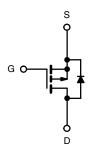
PRODUCT SUMMARY					
V <sub>DS</sub> (V)	$r_{DS(on)}\left(\Omega\right)$	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ)		
- 100	0.017 at V <sub>GS</sub> = - 10 V	- 50	55 nC		
	0.021 at V <sub>GS</sub> = - 4.5 V	- 47	33 110		

### **FEATURES**

• TrenchFET® Power MOSFET







P-Channel MOSFET

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V <sub>DS</sub>	- 100	V	
Gate-Source Voltage		V <sub>GS</sub>	± 20	¬	
	T <sub>C</sub> = 25 °C		- 50 <sup>a</sup>		
Continuous Drain Current /T 175 °C)	T <sub>C</sub> = 70 °C		- 42.5 <sup>a</sup>		
Continuous Drain Current (T <sub>J</sub> = 175 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	- 12.5 <sup>b, c</sup>		
	T <sub>A</sub> = 70 °C		- 10.5 <sup>b, c</sup>		
Pulsed Drain Current		I <sub>DM</sub>	- 40	A .	
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	,	- 50 <sup>a</sup>		
	T <sub>A</sub> = 25 °C	l <sub>S</sub>	- 6.9 <sup>b, c</sup>	7	
Avalanche Current	1 0.1 ml l	I <sub>AS</sub>	- 45		
Single-Pulse Avalanche Energy	L = 0.1 mH	E <sub>AS</sub>	101	mJ	
	T <sub>C</sub> = 25 °C		136		
Maximum Power Dissipation	T <sub>C</sub> = 70 °C	В	95	14/	
	T <sub>A</sub> = 25 °C	P <sub>D</sub>	8.3 <sup>b, c</sup>	W	
	T <sub>A</sub> = 70 °C		5.8 <sup>b, c</sup>		
Operating Junction and Storage Temperature Ra	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 175	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>b, d</sup>	t ≤ 10 sec	$R_{thJA}$	15	18	°C/W	
Maximum Junction-to-Case (Drain)	Steady State	$R_{thJC}$	0.85	1.1	C/VV	

- Notes:
  a. Package limited.
  b. Surface mounted on 1" x 1" FR4 board.
- c. t=10 sec. d. Maximum under steady state conditions is 40 °C/W.

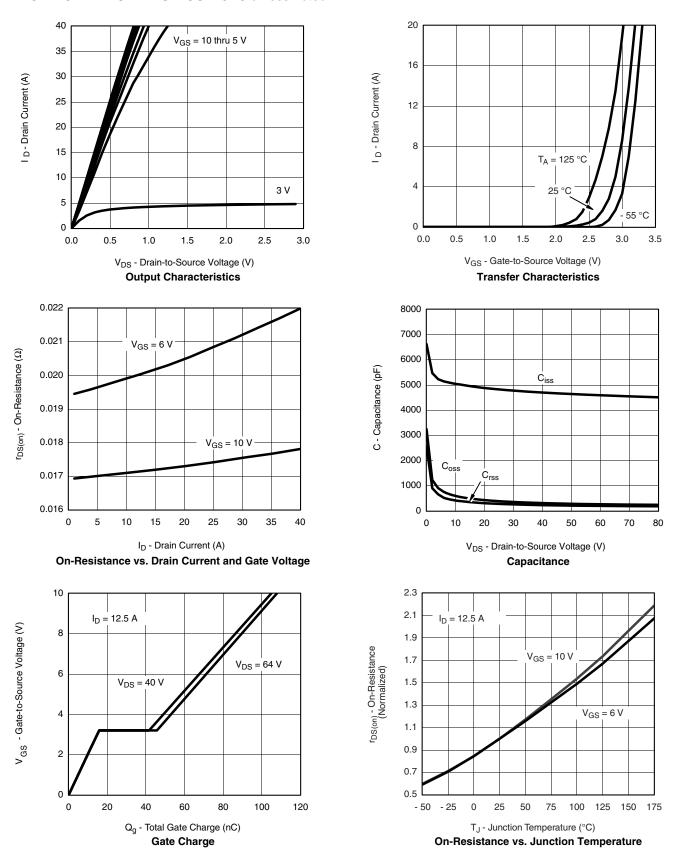


Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit	
Static	<u> </u>				l		
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V, } I_D = -250 \mu\text{A}$	- 100			٧	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 250A		- 73		mV/°C	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = - 250 μA		- 5.5			
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 1		- 3	٧	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = - 100 V, V <sub>GS</sub> = 0 V			- 1	μА	
		V <sub>DS</sub> = - 100 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			- 10		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = -10 \text{ V}$				Α	
Drain-Source On-State Resistance <sup>a</sup>		V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 12.5 A		0.017			
	r <sub>DS(on)</sub>	V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 10.5 A		0.021		Ω	
Forward Transconductance <sup>a</sup>	g <sub>fs</sub>	V <sub>DS</sub> = - 15 V, I <sub>D</sub> = - 12.5 A		52		S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>			4700		pF	
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> = - 50 V, V <sub>GS</sub> = 0 V, f = 1 MHz		320			
Reverse Transfer Capacitance	C <sub>rss</sub>			235			
Total Gate Charge	Qg	V <sub>DS</sub> = -50 V, V <sub>GS</sub> = -10 V, I <sub>D</sub> = -12.5 A		105	160	nC	
		20 1 GO 1 2		55	85		
Gate-Source Charge	$Q_{gs}$	V <sub>DS</sub> = - 50 V, V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 12.5 A		16			
Gate-Drain Charge	Q <sub>gd</sub>			26			
Gate Resistance	R <sub>g</sub>	f = 1 MHz		4		Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			45	70	- ns	
Rise Time	t <sub>r</sub>	$V_{DD} = -50 \text{ V}, R_{L} = 3.8 \Omega$		220	330		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong$ - 10.5 A, $V_{GEN}$ = - 10 V, $R_g$ = 1 $\Omega$		95	145		
Fall Time	t <sub>f</sub>	1		110	165		
Turn-On Delay Time	t <sub>d(on)</sub>			15	25	ns	
Rise Time	t <sub>r</sub>	$V_{DD} = -40 \text{ V, R}_{L} = 3.8 \Omega$		25	40		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong$ - 10.5 A, $V_{GEN}$ = - 4.5 V, $R_g$ = 1 $\Omega$		105	160		
Fall Time	t <sub>f</sub>	1		100	150		
<b>Drain-Source Body Diode Characteristic</b>	s						
Continuous Source-Drain Diode Current	Is	T <sub>C</sub> = 25 °C			- 50	А	
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				- 40		
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = - 10.5 A		- 0.8	- 1.2	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			55	85	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	10.5 4 di/d+ 100.4/ T 05.00		110	165	nC	
Reverse Recovery Fall Time	ta	$I_F = -10.5 \text{ A, di/dt} = 100 \text{ A/}\mu\text{s, T}_J = 25 ^{\circ}\text{C}$		37			
Reverse Recovery Rise Time	t <sub>b</sub>	1		18		- ns	

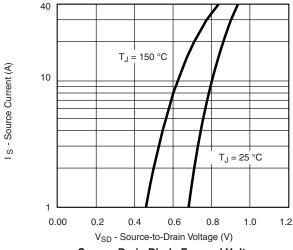
- a. Pulse test; pulse width  $\leq$  300  $\mu s,$  duty cycle  $\leq$  2 %. b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

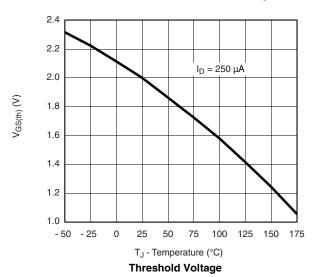






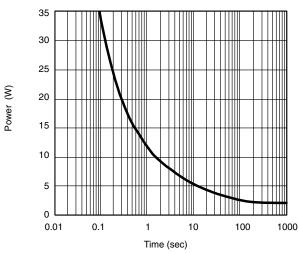




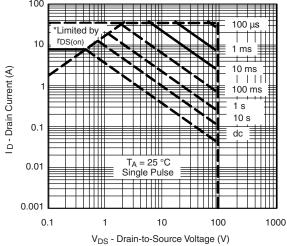


0.05  $r_{\text{DS(on)}}$  - Drain-to-Source On-Resistance  $(\Omega)$ 0.04 T<sub>A</sub> = 125 °C 0.03  $T_A = 25$  °C 0.02 0.01 2 3 6 9 10 V<sub>GS</sub> - Gate-to-Source Voltage (V)

On-Resistance vs. Gate-to-Source Voltage



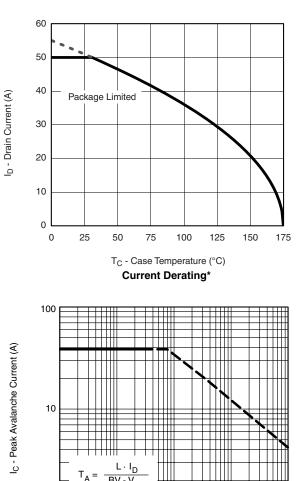
Single Pulse Power, Junction-to-Ambient

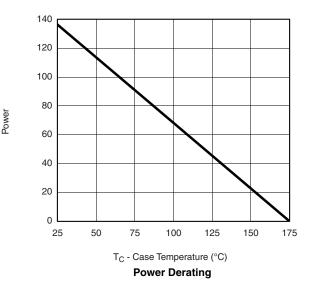


 $\rm V_{DS}$  - Drain-to-Source Voltage (V)  $\rm ^*V_{GS}$  > minimum V  $_{GS}$  at which  $\rm r_{DS(on)}$  is specified

Safe Operating Area, Junction-to-Ambient





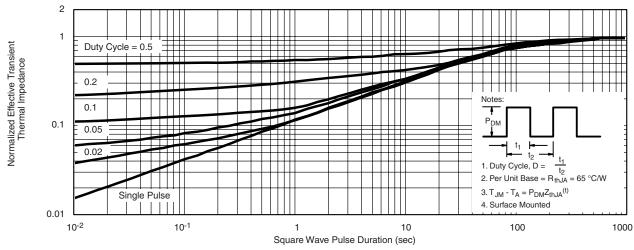


0.000001 0.00001 0.0001 0.001 0.01 T<sub>A</sub> - Time In Avalanche (sec)

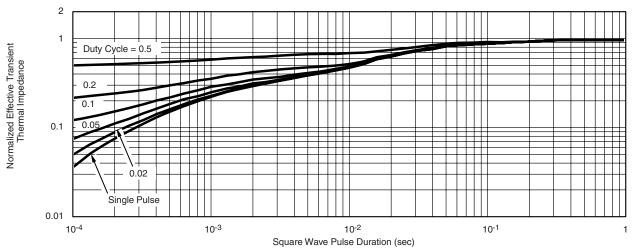
Single Pulse Avalanche Capability

<sup>\*</sup>The power dissipation  $P_D$  is based on  $T_{J(max)}$  = 175 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case



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